

SW60N04V-VB Datasheet N-Channel 40-V (D-S) MOSFET

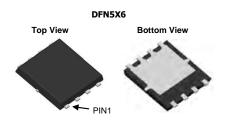
PRODUCT SUMMARY					
V _{DS} (V)	R_{DS(on)} (Ω)	I _D (A) ^a	Q _g (Typ.)		
40	0.0025 at V _{GS} = 10 V	120	38 nC		
	0.0028 at V _{GS} = 6.5 V	105	30 110		

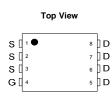
FEATURES

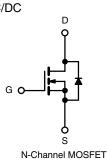
- Halogen-free According to IEC 61249-2-21 Definition
- Trench Power MOSFET
- 100 % R_g Tested •
- 100 % UIS Tested •

APPLICATIONS

- Synchronous Rectification
- Secondary Side DC/DC







Parameter	Symbol	Limit	Unit		
Drain-Source Voltage		V _{DS}	40	V	
Gate-Source Voltage		V _{GS}	± 20		
	T _C = 25 °C		120		
Continuous Drain Current ($T_1 = 150 \ ^{\circ}C$)	T _C = 70 °C	I _D	80		
	T _A = 25 °C	D	33 ^{b, c}		
	T _A = 70 °C		26 ^{b, c}	A	
Pulsed Drain Current	·	I _{DM}	360		
Continuous Source-Drain Diode Current	T _C = 25 °C	I _S	100		
Continuous Source-Drain Diode Current	T _A = 25 °C	'S	4.9 ^{b, c}		
Single Pulse Avalanche Current	L = 0.1 mH	I _{AS}	40		
Single Pulse Avalanche Energy	L = 0.1 IIIH	E _{AS}	80	mJ	
	T _C = 25 °C		83		
Maximum Power Dissipation	T _C = 70 °C	P _D	53	w	
	T _A = 25 °C	' D	5.4 ^{b, c}	~~~~	
	T _A = 70 °C		3.4 ^{b, c}		
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to 150		
Soldering Recommendations (Peak Temperature		260			

THERMAL RESISTANCE RATINGS								
Parameter		Symbol	Typical	Maximum	Unit			
Maximum Junction-to-Ambient ^{b, f}	t ≤ 10 s	R _{thJA}	18	23	°C/W			
Maximum Junction-to-Case (Drain)	Steady State	R _{thJC}	1.0	1.5	0/11			

Notes:

a. Based on $T_C = 25 \text{ °C}$. b. Surface mounted on 1" x 1" FR4 board.

c. t = 10 s.

d. Maximum under steady state conditions is 90 °C/W.

e. Calculated based on maximum junction temperature. Package limitation current is 80 A.

RoHS

COMPLIANT

Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit
Static	-					•
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	40			V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	L 050		43		mV/°C
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I _D = 250 μA		- 6		
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = 250 \ \mu A$	2.0		4.0	V
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 V, V_{GS} = \pm 20 V$			± 100	nA
		$V_{DS} = 40 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$			1	μΑ
Zero Gate Voltage Drain Current	IDSS	$V_{DS} = 40 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 55 ^{\circ}\text{C}$			10	
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, \text{ V}_{GS} = 10 \text{ V}$	100			A
		V _{GS} = 10 V, I _D = 20 A		0.0025		
Drain-Source On-State Resistance ^a	R _{DS(on)}	V _{GS} =6.5 V, I _D = 20 A				Ω
Forward Transconductance ^a	9 _{fs}	V _{DS} = 15 V, I _D = 20 A		102		S
Dynamic ^b				<u> </u>		<u> </u>
Input Capacitance	C _{iss}			4750		
Output Capacitance	C _{oss}	V _{DS} = 20 V, V _{GS} = 0 V, f = 1 MHz		610		pF
Reverse Transfer Capacitance	C _{rss}			275		
Table Oaks Oksawa		$V_{DS} = 20 \text{ V}, \text{ V}_{GS} = 10 \text{ V}, \text{ I}_{D} = 20 \text{ A}$		78	3 117	
Total Gate Charge	Qg			38	57	nC
Gate-Source Charge	Q _{gs}	V_{DS} = 20 V, V_{GS} = 4.5 V, I_D = 20 A		13		
Gate-Drain Charge	Q _{gd}			11		
Gate Resistance	Rg	f = 1 MHz	0.2	0.7	1.4	Ω
Turn-On Delay Time	t _{d(on)}			14	25	- ns
Rise Time	t _r	V_{DD} = 20 V, R_L = 2 Ω		9	18	
Turn-Off Delay Time	t _{d(off)}	$I_D \cong$ 10 A, V_{GEN} = 10 V, R_g = 1 Ω		41	65	
Fall Time	t _f			9	18	
Turn-On Delay Time	t _{d(on)}			33	42	
Rise Time	t _r	V_{DD} = 20 V, R_L = 2 Ω		22	35	
Turn-Off Delay Time	t _{d(off)}	$I_D \cong$ 10 A, V_{GEN} = 4.5 V, R_g = 1 Ω		42	65	
Fall Time	t _f			13	25	
Drain-Source Body Diode Characteris	tics					
Continuous Source-Drain Diode Current	۱ _S	T _C = 25 °C		50		А
Pulse Diode Forward Current ^a	I _{SM}			60		
Body Diode Voltage	V_{SD}	I _S = 5 A		0.75	1.1	V
Body Diode Reverse Recovery Time	t _{rr}			40	60	ns
Body Diode Reverse Recovery Charge	Q _{rr}	l _F = 10 A, dl/dt = 100 A/μs, T _J = 25 °C		48	72	nC
Reverse Recovery Fall Time	t _a	$F = 10 \text{ A}, \text{ and } = 100 \text{ A/} \mu \text{s}, 1 \text{ J} = 25 \text{ C}$		24		
Reverse Recovery Rise Time	t _b	t _b		16		ns

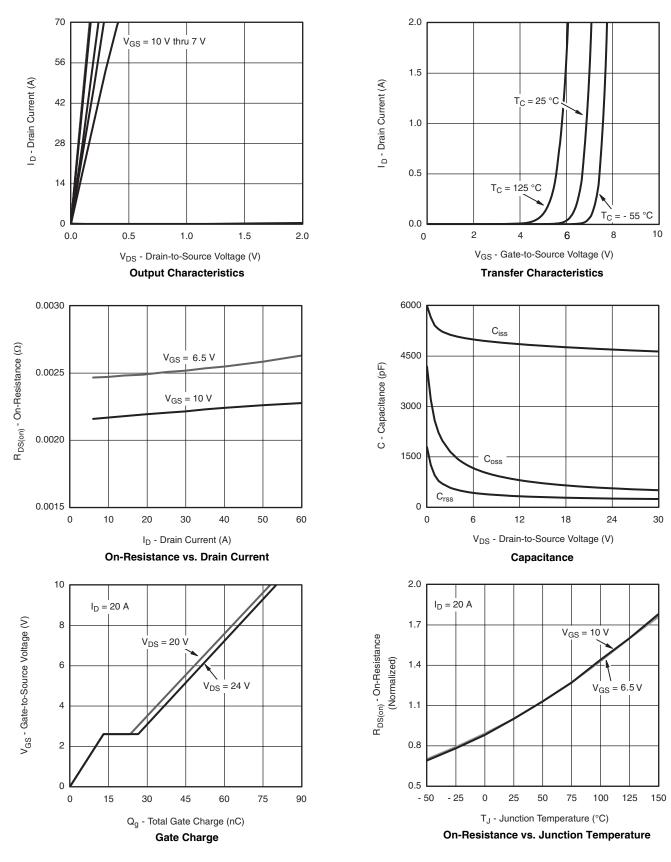
Notes:

a. Pulse test; pulse width \leq 300 $\mu s,$ duty cycle \leq 2 %.

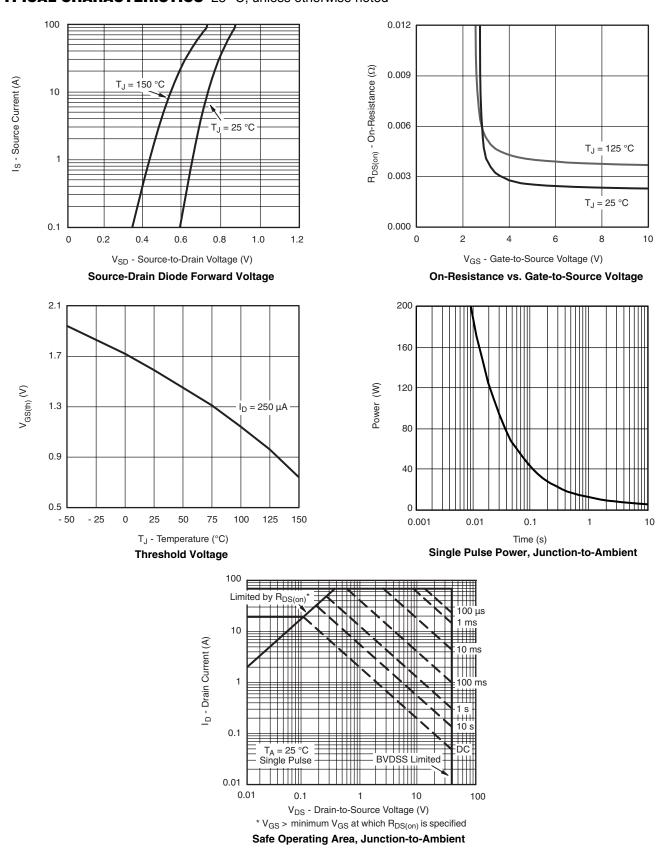
b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

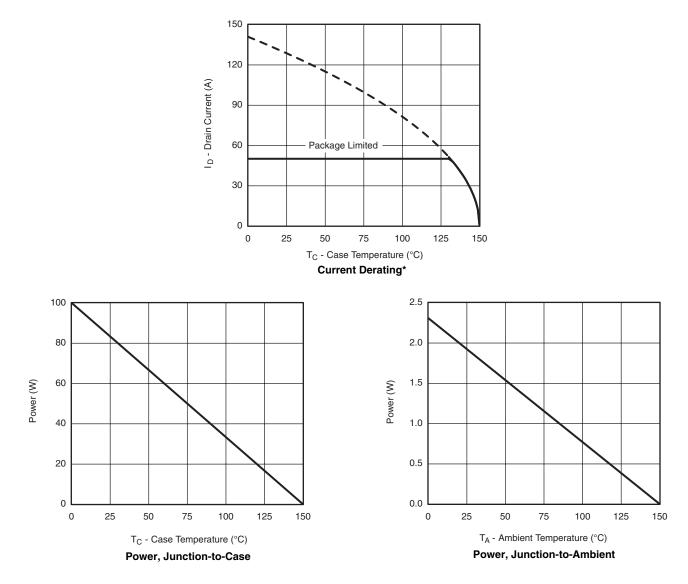






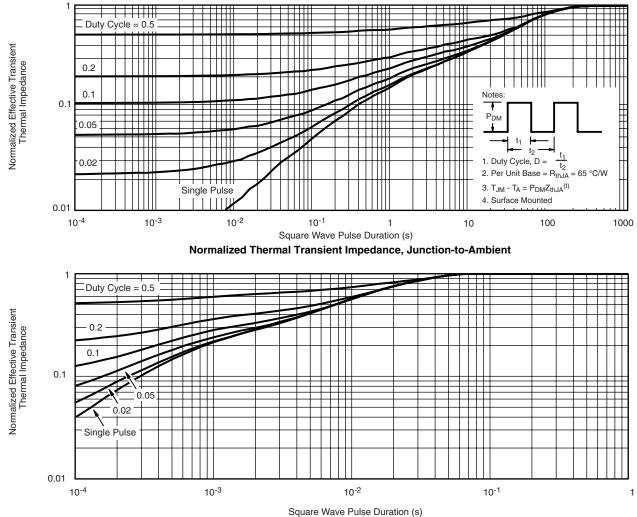






* The power dissipation P_D is based on $T_{J(max)}$ = 150 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.



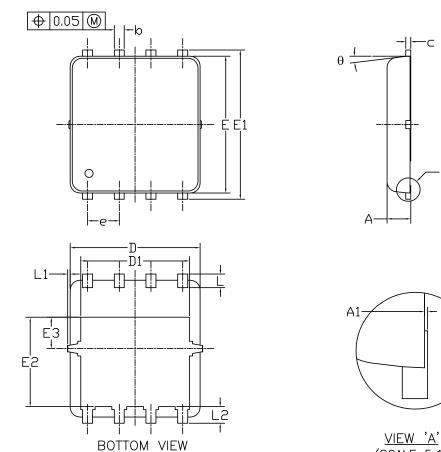


Normalized Thermal Transient Impedance, Junction-to-Case



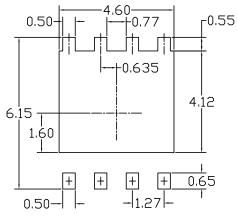
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VIEW 'A'



DFN5x6_8L_EP1_P PACKAGE OUTLIN

RECOMMENDED LAND PATTERN



SYMBOLS	DIMENS	IONS IN MILLI	METERS	DIMENSIONS IN INCHES			
SIMBOLS	MIN	NOM	MAX	MIN	NOM	MAX	
А	0.85	0.95	1.00	0.033	0.037	0.039	
A1	0.00		0.05	0.000		0.002	
b	0.30	0.40	0.50	0.012	0.016	0.020	
с	0.15	0.20	0.25	0.006	0.008	0.010	
D	5.10	5.20	5.30	0.201	0.205	0.209	
D1	4.25	4.35	4.45	0.167	0.171	0.175	
E	5.45	5.55	5.65	0.215	0.219	0.222	
E1	5.95	6.05	6.15	0.234	0.238	0.242	
E2	3.525	3.625	3.725	0.139	0.143	0.147	
E3	1.175	1.275	1.375	0.046	0.050	0.054	
e	1.27 BSC			0.050 BSC			
L	0.45	0.55	0.65	0.018	0.022	0.026	
L1	0		0.15	0		0.006	
L2	0.68 REF			0.027 REF			
θ	0°		10°	0°		10°	

(SCALE 5:1)

NOTE

1. PACKAGE BODY SIZES EXCLUDE MOLD FLASH AND GATE BURRS. MOLD FLASH AT THE NON-LEAD SIDES SHOULD BE LESS THAN 6 MILS EACH. 2. CONTROLLING DIMENSION IS MILLIMETER.

CONVERTED INCH DIMENSIONS ARE NOT NECESSARILY EXACT.

UNIT: mm



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